

UNISONIC TECHNOLOGIES CO., LTD

2N70ZL **Power MOSFET**

2A, 700V N-CHANNEL **POWER MOSFET**

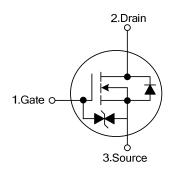
DESCRIPTION

The UTC 2N70ZL is a high voltage MOSFET designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

FEATURES

- * $R_{DS(ON)} = 6.3\Omega@V_{GS} = 10V$
- * Ultra Low gate charge (typical 8.1nC)
- * Low reverse transfer capacitance (C_{RSS} = typical 5.0 pF)
- * Fast switching capability
- * Avalanche energy specified
- * Improved dv/dt capability, high ruggedness

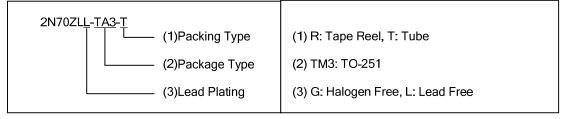
SYMBOL

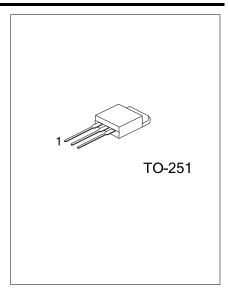


ORDERING INFORMATION

Ordering Number		Daakana	Pin Assignment			Doolsing	
Lead Free	Halogen Free	Package	1	2	3	Packing	
2N70ZLL-TM3-T	2N70ZLG-TM3-T	TO-251	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source





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■ **ABSOLUTE MAXIMUM RATINGS** (T_C = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	700	V
Gate-Source Voltage		V_{GSS}	±30	V
Avalanche Current (Note 2)		I _{AR}	2.0	Α
Drain Current	Continuous	I _D	2.0	Α
	Pulsed (Note 2)	I _{DM}	8.0	Α
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	140	mJ
	Repetitive (Note 2)	E _{AR}	2.8	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4.5	V/ns
Power Dissipation		P_D	30	W
Junction Temperature		TJ	+150	°C
Operating Temperature		T _{OPR}	-55 ~ +150	°C
Storage Temperature		T _{STG}	-55 ~ +150	°C

- Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

 Absolute maximum ratings are stress ratings only and functional device operation is not implied.
 - 2. Repetitive Rating : Pulse width limited by $T_{\rm J}$
 - 3. L=45mH, I_{AS} =2.0A, V_{DD} =50V, R_{G} =25 Ω , Starting T_{J} = 25°C
 - 4. $I_{SD} \le 2.0A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	110	°C/W	
Junction to Case	θЈс	4.24	°C/W	

■ ELECTRICAL CHARACTERISTICS (T_J =25°C, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage		BV _{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	700			V	
Drain-Source Leakage Current		I _{DSS}	$V_{DS} = 700V, V_{GS} = 0V$			10	μΑ	
Gate-Source Leakage Current	Forward	lee	$V_{GS} = 30V, V_{DS} = 0V$			100	nA	
	Reverse		$V_{GS} = -30V, V_{DS} = 0V$			-100	nA	
Breakdown Voltage Temperature Coefficient		$\triangle BV_{DSS}/\triangle T_{J}$	I_D = 250 μ A, Referenced to 25°C		0.4		V/°C	
ON CHARACTERISTICS								
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V	
Static Drain-Source On-State Resistance		R _{DS(ON)}	$V_{GS} = 10V, I_{D} = 1A$		5.0	6.3	Ω	
DYNAMIC CHARACTERISTICS								
Input Capacitance		C _{ISS}			270	350	pF	
Output Capacitance		Coss	V _{DS} =25V, V _{GS} =0V, f =1MHz		38	50	pF	
Reverse Transfer Capacitance		C _{RSS}			5	7	pF	

■ ELECTRICAL CHARACTERISTICS(Cont.)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
SWITCHING CHARACTERISTICS								
Turn-On Delay Time	t _{D (ON)}				30	ns		
Turn-On Rise Time	t_R	$V_{DD} = 350V$, $I_D = 2.0A$, $R_G = 25\Omega$			80	ns		
Turn-Off Delay Time	t _{D(OFF)}	(Note 1, 2)			50	ns		
Turn-Off Fall Time	t₅				70	ns		
Total Gate Charge	Q_{G}	V -560V V -40V I -2.0A		8.1	11	nC		
Gate-Source Charge	Q_{GS}	V _{DS} =560V, V _{GS} =10V, I _D =2.0A		1.7		nC		
Gate-Drain Charge	Q_{GD}	(Note 1, 2)		4.4		nC		
DRAIN-SOURCE DIODE CHARACTERISTICS								
Drain-Source Diode Forward Voltage	V_{SD}	$V_{GS} = 0 \text{ V}, I_{SD} = 2.0 \text{ A}$			1.4	V		
Continuous Drain-Source Current	I _{SD}				2.0	Α		
Pulsed Drain-Source Current	I _{SM}				8.0	Α		
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V}, I_{SD} = 2.0 \text{A}$		260		ns		
Reverse Recovery Charge	Q _{RR}	di/dt = 100 A/µs (Note1)		1.09		μC		

Notes: 1. Pulse Test: Pulse width≤300µs, Duty cycle≤2%

2. Essentially independent of operating temperature

■ TEST CIRCUITS AND WAVEFORMS

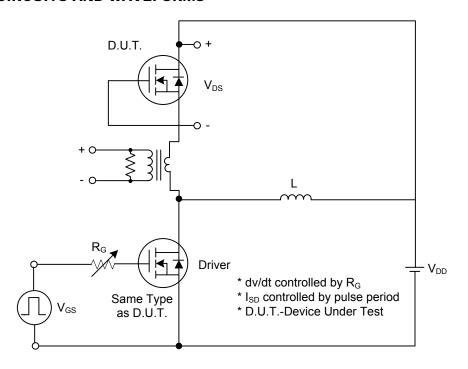


Fig. 1A Peak Diode Recovery dv/dt Test Circuit

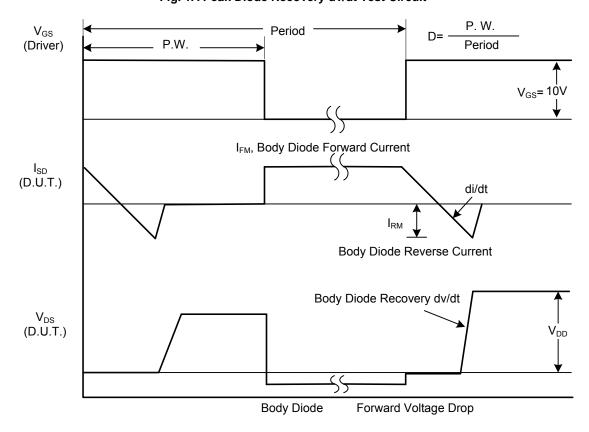
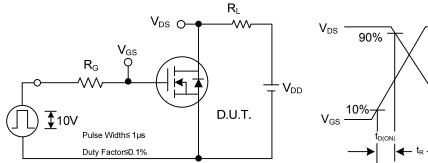


Fig. 1B Peak Diode Recovery dv/dt Waveforms

■ TEST CIRCUITS AND WAVEFORMS (Cont.)



V_{DS} 90%

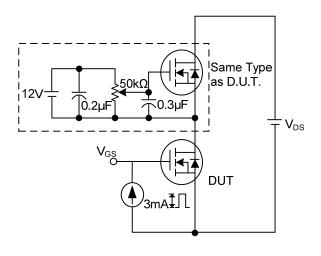
V_{GS} 10%

t_{D(ON)}

t_R →

Fig. 2A Switching Test Circuit

Fig. 2B Switching Waveforms



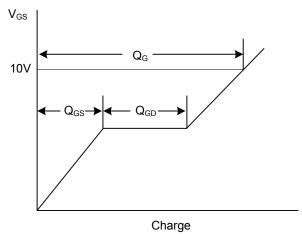
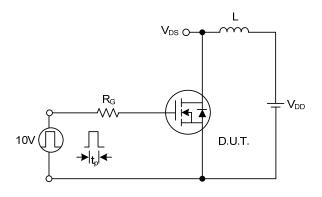


Fig. 3A Gate Charge Test Circuit

Fig. 3B Gate Charge Waveform



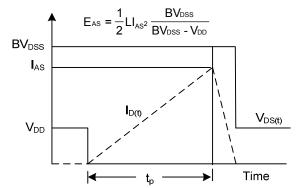
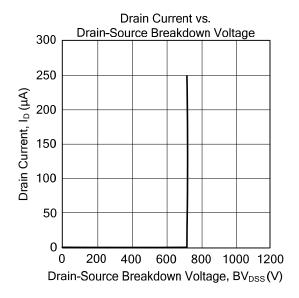
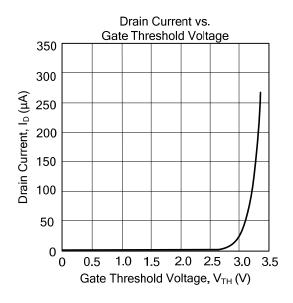


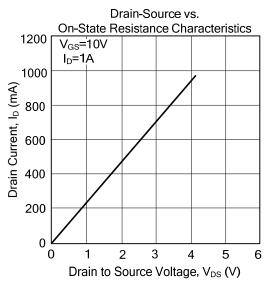
Fig. 4A Unclamped Inductive Switching Test Circuit

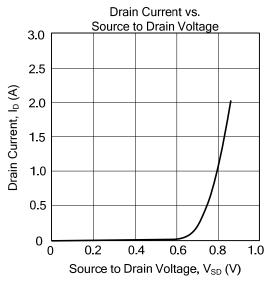
Fig. 4B Unclamped Inductive Switching Waveforms

■ TYPICAL CHARACTERISTICS









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